

Fig. 1: Graphic depicting the cross-section of one Anode-Cathode pair

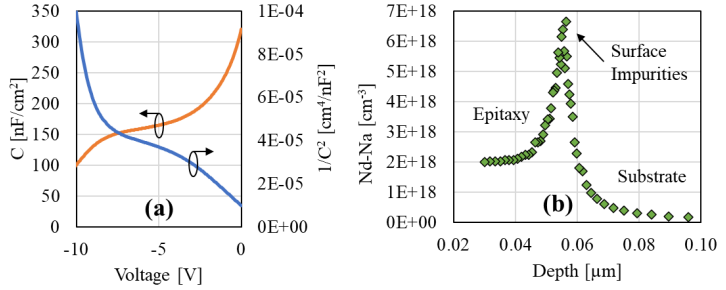


Fig. 2: (a) C-V test structure response and (b) extracted carrier concentration with respect to depth

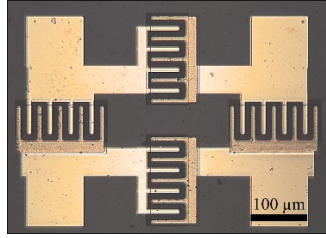


Fig. 3: Rectifier IC microscope image

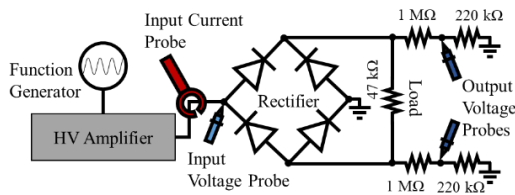


Fig. 4: Rectifier IC test setup

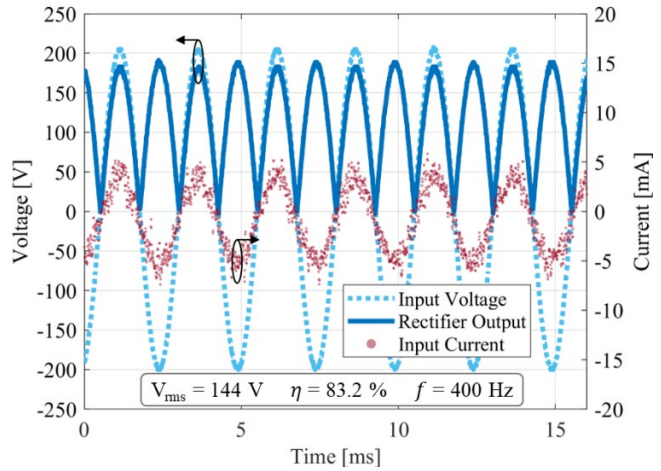


Fig. 5: Rectifier IC input and output waveforms

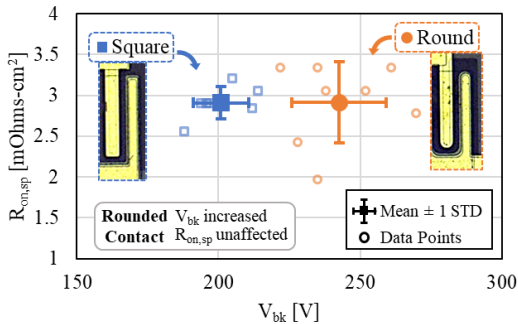


Fig. 6: Analysis comparing the effect of contact geometries on $R_{on,sp}$ and V_{bk}

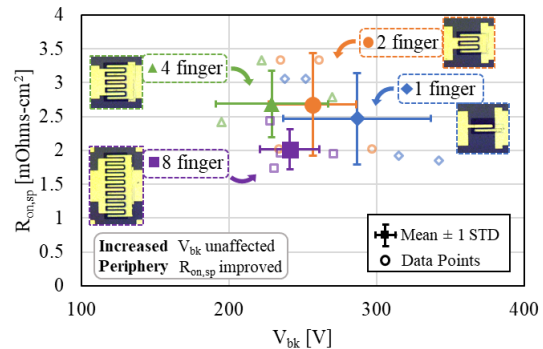


Fig. 7: Analysis comparing the effect of additional anode-cathode pairs on $R_{on,sp}$ and V_{bk}

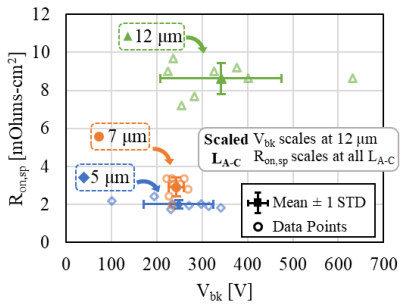


Fig. 8: Analysis comparing the effect of L_{A-C} on $R_{on,sp}$ and V_{bk}

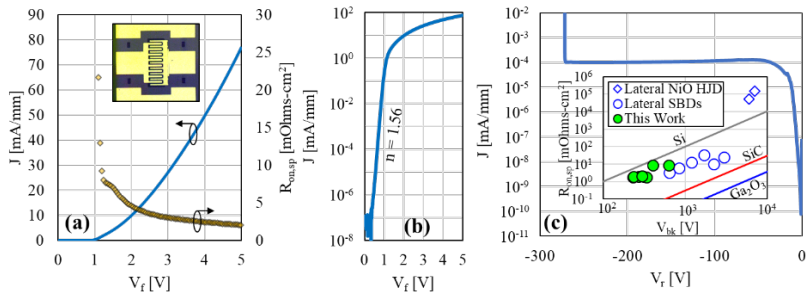


Fig. 9: Forward (a-b) and reverse (c) J-V response of a select diode, with a comparison to published results inset to (c)